or less of an overall diameter, and in which there exists, surrounding the OSF ring, a defect free zone occupying 50% or more of a total surface area (on one side).

6. (once amended) A silicon single crystal wafer, obtained from the silicon single crystal ingot of claim 2, wherein there exists an OSF ring an inner diameter of which is 50% or less of an overall diameter, and in which there exists, surrounding the OSF ring, a defect free zone occupying 75% or more of a total surface area (on one side).

Respectfully submitted,

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